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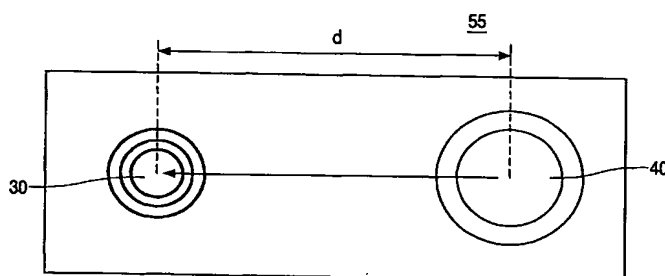
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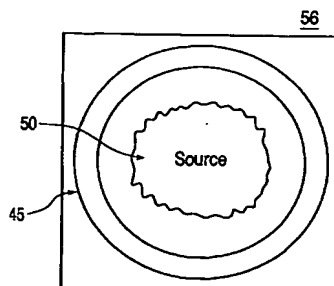
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[Continued on next page]

(54) Title: METHOD OF MEASURING THE PERFORMANCE OF AN ILLUMINATION SYSTEM



a



b

(57) Abstract: The performance of an illumination system in, for example, a lithographic projection apparatus can be measured accurately and reliably by means of a test object (55) comprising at least one Fresnel zone lens (30) and an associated reference mark, preferably a ring (40). By superposed imaging of these and detecting and evaluating the composed image (56), telecentricity errors and aberrations of the illumination can be measured.

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